

<b>Notice of References Cited</b>	Application/Control No. 10/624,327	Applicant(s)/Patent Under Reexamination LEE ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0105017	08-2002	Kim et al.	257/295
	B	US-2002/0196653	12-2002	Kim et al.	365/100
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	K	US-			
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	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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